

- LIN functionality working either as master or slave LIN device
- Extended support for LIN-Protocol to reduce interrupt load

A/D converter

- SAR-type
- 8/10-bit resolution
- Signals interrupt on conversion end, single conversion mode, continuous conversion mode, stop conversion mode, activation by software, external trigger, reload timers and PPGs
- Range Comparator Function

Source Clock Timers

Three independent clock timers (23-bit RC clock timer, 23-bit Main clock timer, 17-bit Sub clock timer)

Hardware Watchdog Timer

- Hardware watchdog timer is active after reset
- Window function of Watchdog Timer is used to select the lower window limit of the watchdog interval

Reload Timers

- 16-bit wide
- Prescaler with 1/2¹, 1/2², 1/2³, 1/2⁴, 1/2⁵, 1/2⁶ of peripheral clock frequency
- Event count function

Free-Running Timers

- Signals an interrupt on overflow, supports timer clear upon match with Output Compare (0, 4)
- Prescaler with 1, 1/2¹, 1/2², 1/2³, 1/2⁴, 1/2⁵, 1/2⁶, 1/2⁷, 1/2⁸ of peripheral clock frequency

Input Capture Units

- 16-bit wide
- Signals an interrupt upon external event
- Rising edge, Falling edge or Both (rising & falling) edges sensitive

Output Compare Units

- 16-bit wide
- Signals an interrupt when a match with Free-running Timer occurs
- A pair of compare registers can be used to generate an output signal

Programmable Pulse Generator

- 16-bit down counter, cycle and duty setting registers
- Can be used as 2 ×8-bit PPG
- Interrupt at trigger, counter borrow and/or duty match
- PWM operation and one-shot operation

- Internal prescaler allows 1, 1/4, 1/16, 1/64 of peripheral clock as counter clock or of selected Reload timer underflow as clock input
- Can be triggered by software or reload timer
- Can trigger ADC conversion
- Timing point capture

Quadrature Position/Revolution Counter (QPRC)

- Up/down count mode, Phase difference count mode, Count mode with direction
- 16-bit position counter
- 16-bit revolution counter
- Two 16-bit compare registers with interrupt
- Detection edge of the three external event input pins AIN, BIN and ZIN is configurable

Real Time Clock

- Operational on main oscillation (4MHz), sub oscillation (32kHz) or RC oscillation (100kHz/2MHz)
- Capable to correct oscillation deviation of Sub clock or RC oscillator clock (clock calibration)
- Read/write accessible second/minute/hour registers
- Can signal interrupts every half second/second/minute/hour/day
- Internal clock divider and prescaler provide exact 1s clock

External Interrupts

- Edge or Level sensitive
- Interrupt mask bit per channel
- Each available CAN channel RX has an external interrupt for wake-up
- Selected USART channels SIN have an external interrupt for wake-up

Non Maskable Interrupt

- Disabled after reset, can be enabled by Boot-ROM depending on ROM configuration block
- Once enabled, can not be disabled other than by reset
- High or Low level sensitive
- Pin shared with external interrupt 0

I/O Ports

- Most of the external pins can be used as general purpose I/O
- All push-pull outputs
- Bit-wise programmable as input/output or peripheral signal
- Bit-wise programmable input enable
- One input level per GPIO-pin (either Automotive or CMOS hysteresis)
- Bit-wise programmable pull-up resistor



Built-in On Chip Debugger (OCD)

- One-wire debug tool interface
- Break function:
 - ☐ Hardware break: 6 points (shared with code event)
 - □ Software break: 4096 points
- Event function
 - □ Code event: 6 points (shared with hardware break)
 - □ Data event: 6 points
 - □ Event sequencer: 2 levels + reset
- Execution time measurement function
- Trace function: 42 branches
- Security function

Flash Memory

- Dual operation flash allowing reading of one Flash bank while programming or erasing the other bank
- Command sequencer for automatic execution of programming algorithm and for supporting DMA for programming of the Flash Memory
- Supports automatic programming, Embedded Algorithm
- Write/Erase/Erase-Suspend/Resume commands
- A flag indicating completion of the automatic algorithm
- Erase can be performed on each sector individually
- Sector protection
- Flash Security feature to protect the content of the Flash
- Low voltage detection during Flash erase or write

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1. Product Lineup

	Features		MB96610	Remark
Product Type		Flash Memory Product	-	
Subclock		Subclock can be set by software		
Dual Operation Flash Memory RAM		-		
32.5KB + 32		4KB	MB96F612R, MB96F612A	Product Options
64.5KB + 32	KB	10KB	MB96F613R, MB96F613A	R: MCU with CAN
128.5KB + 3	2KB	10KB	MB96F615R, MB96F615A	A: MCU without CAN
Package		LQFP-48 LQA048		
DMA			2ch	
USART			3ch	LIN-USART 2/7/8
	with automatic LIN-Heatransmission/reception	ader	Yes (only 1ch)	LIN-USART 2
	with 16 byte RX- and TX-FIFO		No	
8/10-bit A/D	Converter		16ch	AN 0/1/3/4/6 to 10/ 12/14/16/24/25/30/31
	with Data Buffer		No	
	with Range Comparato	r	Yes	
	with Scan Disable		No	
	with ADC Pulse Detect	ion	No	
16-hit Reload	d Timer (RLT)		3ch	RLT 1/3/6
	Running Timer (FRT)		4ch	FRT 0 to 3 FRT 0 to 3 does not have external clock input pin
16-bit Input 0	Capture Unit (ICU)		7ch (3 channels for LIN-USART)	ICU 0/1/4 to 6/9/10 (ICU 6/9/10 for LIN-USART)
16-bit Output	t Compare Unit (OCU)		5ch	OCU 0/1/4/6/7 (OCU 4 for FRT clear)
8/16-bit Prog	rammable Pulse Genera	tor (PPG)	8ch (16-bit) / 16ch (8-bit)	PPG 0/1/3/4/6/7/12/14
	with Timing point captu		Yes	
	with Start delay		No	
	with Ramp		No	
Quadrature F (QPRC)	Position/Revolution Coun	nter	2ch	QPRC 0/1
CAN Interfac	ce		1ch	CAN 2 32 Message Buffers
External Inte	rrupts (INT)		11ch	INT 0/2/3/4/7 to 13
	ole Interrupt (NMI)		1ch	
	Time Clock (RTC)		1ch	
	(/		35 (Dual clock mode)	
I/O Ports			37 (Single clock mode)	
Clock Calibra	ation Unit (CAL)		1ch	
Clock Output	t Function	·	2ch	
	Detection Function		Yes	Low voltage detection function can be disabled by software
Hardware W	atchdog Timer		Yes	,
On-chip RC-			Yes	
On-chip Deb			Yes	
to:	- 99		<u> </u>	_1

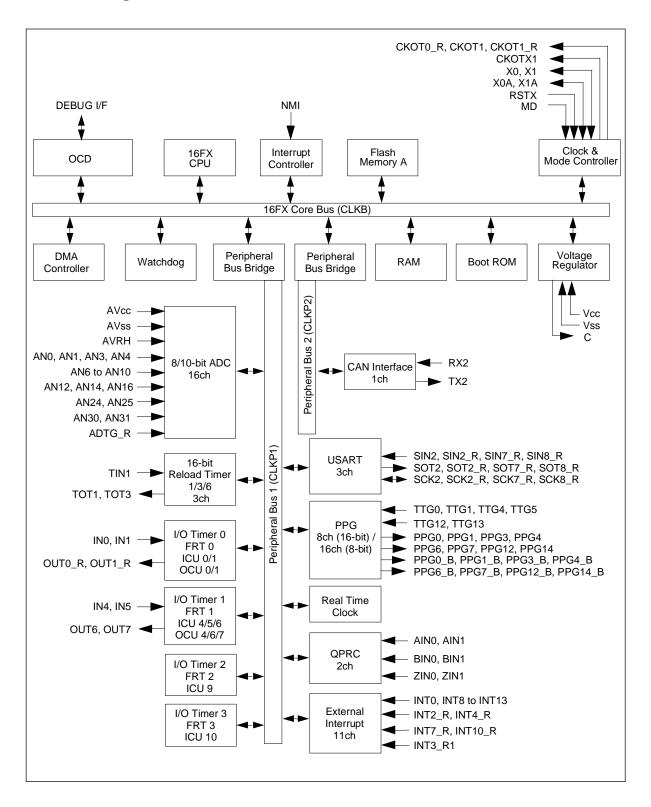
Note:

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All signals of the peripheral function in each product cannot be allocated by limiting the pins of package. It is necessary to use
the port relocate function of the general I/O port according to your function use.

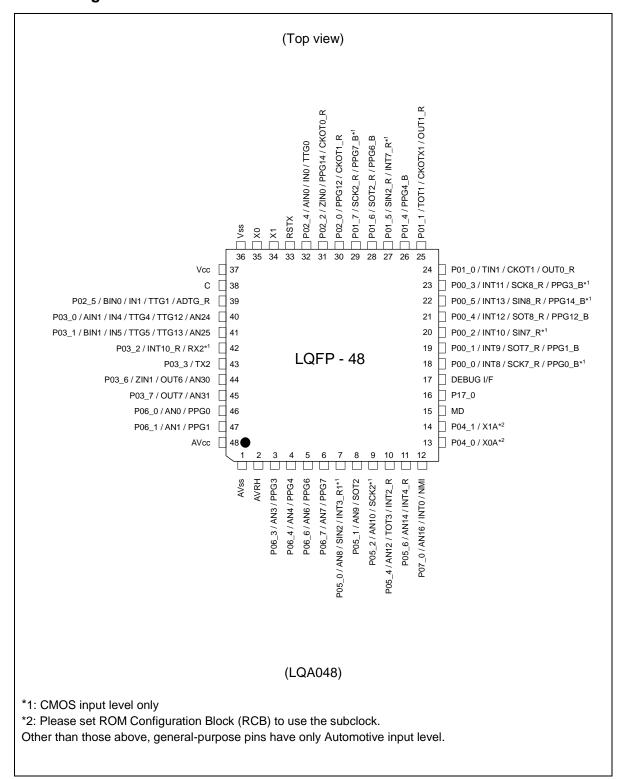


2. Block Diagram





3. Pin Assignment



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4. Pin Description

Pin name	Feature	Description
ADTG_R	ADC	Relocated A/D converter trigger input pin
AINn	QPRC	Quadrature Position/Revolution Counter Unit n input pin
ANn	ADC	A/D converter channel n input pin
AVcc	Supply	Analog circuits power supply pin
AVRH	ADC	A/D converter high reference voltage input pin
AVss	Supply	Analog circuits power supply pin
BINn	QPRC	Quadrature Position/Revolution Counter Unit n input pin
С	Voltage regulator	Internally regulated power supply stabilization capacitor pin
CKOTn	Clock Output function	Clock Output function n output pin
CKOTn_R	Clock Output function	Relocated Clock Output function n output pin
CKOTXn	Clock Output function	Clock Output function n inverted output pin
DEBUG I/F	OCD	On Chip Debugger input/output pin
INn	ICU	Input Capture Unit n input pin
INTn	External Interrupt	External Interrupt n input pin
INTn_R	External Interrupt	Relocated External Interrupt n input pin
INTn_R1	External Interrupt	Relocated External Interrupt n input pin
MD	Core	Input pin for specifying the operating mode
NMI	External Interrupt	Non-Maskable Interrupt input pin
OUTn	OCU	Output Compare Unit n waveform output pin
OUTn_R	OCU	Relocated Output Compare Unit n waveform output pin
Pnn_m	GPIO	General purpose I/O pin
PPGn	PPG	Programmable Pulse Generator n output pin (16bit/8bit)
PPGn_B	PPG	Programmable Pulse Generator n output pin (16bit/8bit)
RSTX	Core	Reset input pin
RXn	CAN	CAN interface n RX input pin
SCKn	USART	USART n serial clock input/output pin
SCKn_R	USART	Relocated USART n serial clock input/output pin
SINn	USART	USART n serial data input pin
SINn_R	USART	Relocated USART n serial data input pin
SOTn	USART	USART n serial data output pin
SOTn_R	USART	Relocated USART n serial data output pin
TINn	Reload Timer	Reload Timer n event input pin
TOTn	Reload Timer	Reload Timer n output pin
TTGn	PPG	Programmable Pulse Generator n trigger input pin
TXn	CAN	CAN interface n TX output pin
Vcc	Supply	Power supply pin
Vss	Supply	Power supply pin
X0	Clock	Oscillator input pin
X0A	Clock	Subclock Oscillator input pin
X1	Clock	Oscillator output pin
X1A	Clock	Subclock Oscillator output pin
ΛIΛ	CIOCK	Cabelook Cacillator output pill

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Pin name	Feature	Description
ZINn	QPRC	Quadrature Position/Revolution Counter Unit n input pin

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5. Pin Circuit Type

Pin no.	I/O circuit type*	Pin name
1	Supply	AVss
2	G	AVRH
3	К	P06_3 / AN3 / PPG3
4	К	P06_4 / AN4 / PPG4
5	К	P06_6 / AN6 / PPG6
6	К	P06_7 / AN7 / PPG7
7	I	P05_0 / AN8 / SIN2 / INT3_R1
8	К	P05_1 / AN9 / SOT2
9	I	P05_2 / AN10 / SCK2
10	К	P05_4 / AN12 / TOT3 / INT2_R
11	К	P05_6 / AN14 / INT4_R
12	К	P07_0 / AN16 / INT0 / NMI
13	В	P04_0 / X0A
14	В	P04_1 / X1A
15	С	MD
16	Н	P17_0
17	0	DEBUG I/F
18	М	P00_0 / INT8 / SCK7_R / PPG0_B
19	Н	P00_1 / INT9 / SOT7_R / PPG1_B
20	М	P00_2 / INT10 / SIN7_R
21	Н	P00_4 / INT12 / SOT8_R / PPG12_B
22	М	P00_5 / INT13 / SIN8_R / PPG14_B
23	М	P00_3 / INT11 / SCK8_R / PPG3_B
24	Н	P01_0 / TIN1 / CKOT1 / OUT0_R
25	Н	P01_1 / TOT1 / CKOTX1 / OUT1_R
26	Н	P01_4 / PPG4_B
27	М	P01_5 / SIN2_R / INT7_R
28	Н	P01_6 / SOT2_R / PPG6_B
29	М	P01_7 / SCK2_R / PPG7_B
30	Н	P02_0 / PPG12 / CKOT1_R
31	Н	P02_2 / ZIN0 / PPG14 / CKOT0_R
32	Н	P02_4 / AIN0 / IN0 / TTG0
22 23 24 25 26 27 28 29 30 31	M M H H H H H H H H H	P00_5 / INT13 / SIN8_R / PPG14_B P00_3 / INT11 / SCK8_R / PPG3_B P01_0 / TIN1 / CKOT1 / OUT0_R P01_1 / TOT1 / CKOTX1 / OUT1_R P01_4 / PPG4_B P01_5 / SIN2_R / INT7_R P01_6 / SOT2_R / PPG6_B P01_7 / SCK2_R / PPG7_B P02_0 / PPG12 / CKOT1_R P02_2 / ZIN0 / PPG14 / CKOT0_R

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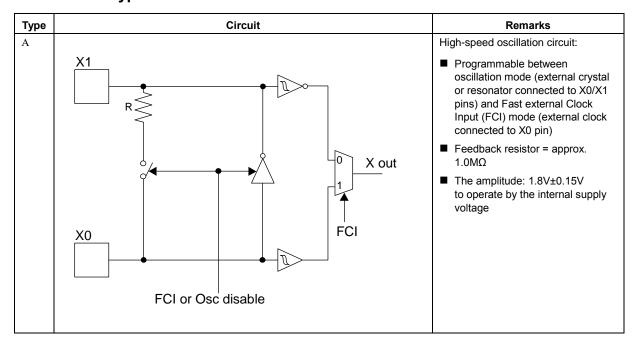
Pin no.	I/O circuit type*	Pin name
33	С	RSTX
34	A	X1
35	A	X0
36	Supply	Vss
37	Supply	Vcc
38	F	С
39	Н	P02_5 / BIN0 / IN1 / TTG1 / ADTG_R
40	К	P03_0 / AIN1 / IN4 / TTG4 / TTG12 / AN24
41	К	P03_1 / BIN1 / IN5 / TTG5 / TTG13 / AN25
42	М	P03_2 / INT10_R / RX2
43	Н	P03_3 / TX2
44	К	P03_6 / ZIN1 / OUT6 / AN30
45	К	P03_7 / OUT7 / AN31
46	К	P06_0 / AN0 / PPG0
47	К	P06_1 / AN1 / PPG1
48	Supply	AVcc

^{*:} See I/O Circuit Type" for details on the I/O circuit types.

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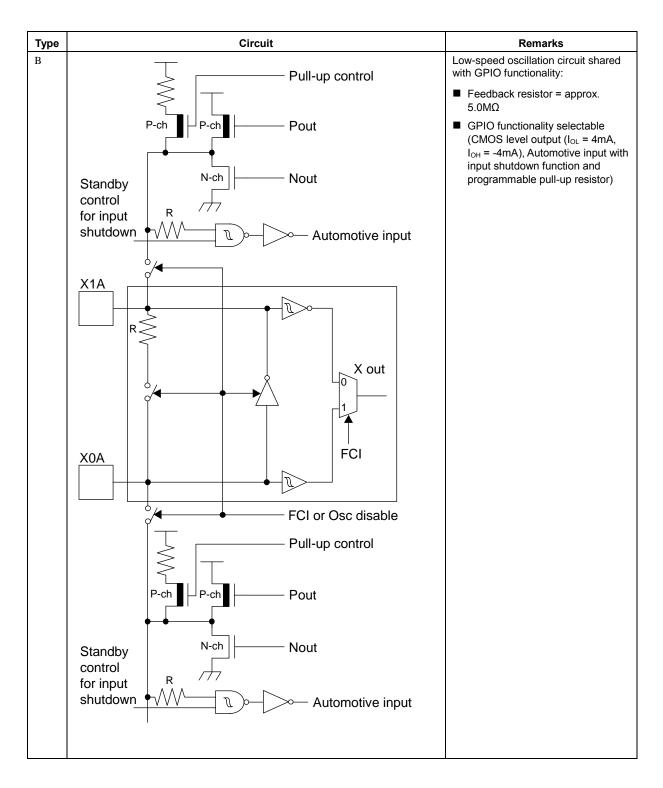
6. I/O Circuit Type



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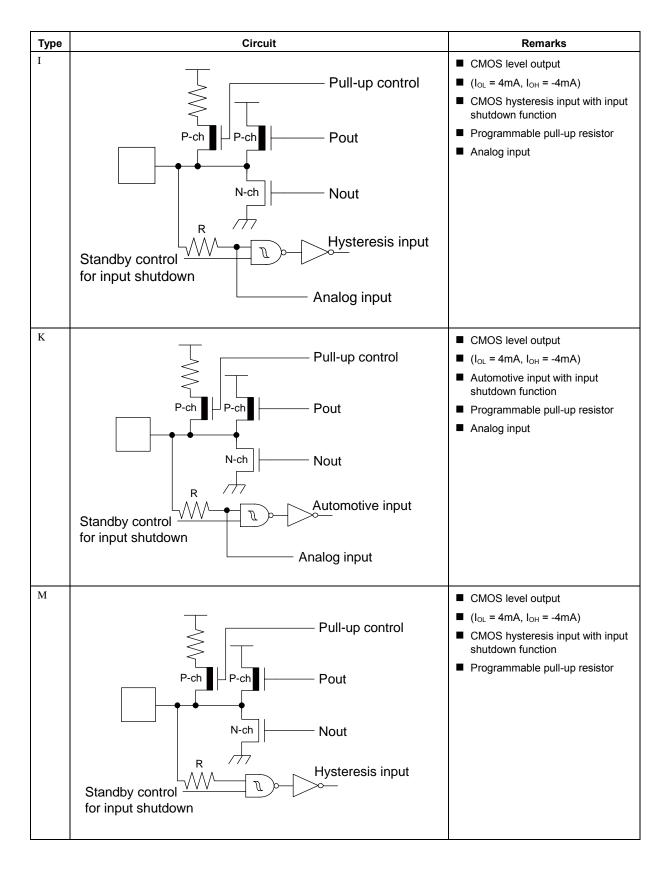
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Туре	Circuit	Remarks
С	R Hysteresis inputs	CMOS hysteresis input pin
F	P-ch N-ch	Power supply input protection circuit
G	P-ch N-ch	 A/D converter ref+ (AVRH) power supply input pin with protection circuit Without protection circuit against V_{CC} for pins AVRH
Н	Pull-up control P-ch P-ch P-ch Nout Nout Automotive input	 ■ CMOS level output ■ (I_{OL} = 4mA, I_{OH} = -4mA) ■ Automotive input with input shutdown function ■ Programmable pull-up resistor

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Туре	Circuit	Remarks
О		Open-drain I/O Output 25mA, Vcc = 2.7V TTL input
	Standby control TTL input	

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7. Memory Map

FF:FF	FF _H	
		USER ROM*1
DE:00		
DD:FF	FFH	
		Reserved
10:000	00н	
0F:C0	00н	Boot-ROM
0E:900	00н	Peripheral
		Reserved
01:000	00 _H	
		ROM/RAM
00:800	00н	MIRROR
		Internal RAM
RAMS	TART0*2	bank0
		Reserved
00:0C	00н	
00:038	80 _H	Peripheral
00:018	30 _H	GPR*3
00:010	00 _H	DMA
00:00F	FO _H	Reserved
00:000	00н	Peripheral

^{*1:} For details about USER ROM area, see "

User ROM Memory Map for Flash Devices" on the following pages.

- *2: For RAMSTART addresses, see the table on the next page.
- *3: Unused GPR banks can be used as RAM area.

GPR: General-Purpose Register

The DMA area is only available if the device contains the corresponding resource.

The available RAM and ROM area depends on the device.

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8. RAMstart Addresses

Devices	Bank 0 RAM size	RAMSTART0
MB96F612	4KB	00:7200 _H
MB96F613, MB96F615	10KB	00:5A00 _н

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9. User ROM Memory Map for Flash Devices

		MB96F612	MB96F613	MB96F615	
CPU mode address	Flash memory mode address	Flash size 32.5KB + 32KB	Flash size 64.5KB + 32KB	Flash size 128.5KB + 32KB	
FF:FFFF _H	3F:FFFF _H	SA39 - 32KB			
FF:8000 _H	3F:8000 _H		SA39 - 64KB	SA39 - 64KB	
FF:7FFF _H FF:0000 _H	3F:7FFF _H 3F:0000 _H				
FE:FFFF _H	3E:FFFF _H				Bank A of F
Larry	OL.IIII			SA38 - 64KB	
FE:0000 _H	3E:0000 _H				
FD:FFFF _H		Reserved	Reserved	Reserved	
DF:A000 _H DF:9FFF _H	1F:9FFF _H	SA4 - 8KB	SA4 - 8KB	SA4 - 8KB	
DF:8000 _H	1F:8000 _H	O/TT OTE	O/TT OILD	O/TT ORD	
DF:7FFF _H	1F:7FFF _H	SA3 - 8KB	SA3 - 8KB	SA3 - 8KB	
DF:6000 _H	1F:6000 _H				Bank B of F
DC-KEEE	1F:4000 _H	SA2 - 8KB	SA2 - 8KB	SA2 - 8KB	
DF:5FFF _H				+	
DF:4000 _H				SA1 - 8KB	
DF:4000 _H DF:3FFF _H	1F:3FFF _H	SA1 - 8KB	SA1 - 8KB	SAI-OND	
DF:4000 _H					- Dank A of F
DF:4000 _H DF:3FFF _H DF:2000 _H	1F:3FFF _H 1F:2000 _H	SA1 - 8KB SAS - 512B*	SA1 - 8KB SAS - 512B*	SAS - 512B*	Bank A of F

^{*:} Physical address area of SAS-512B is from DF:0000_H to DF:01FF_H.

Others (from DF:0200 $_{\mbox{\scriptsize H}}$ to DF:1FFF $_{\mbox{\scriptsize H}}$) is mirror area of SAS-512B.

Sector SAS contains the ROM configuration block RCBA at CPU address DF:0000_H -DF:01FF_H.

SAS can not be used for E²PROM emulation.

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10. Serial Programming Communication Interface

USART pins for Flash serial programming (MD = 0, DEBUG I/F = 0, Serial Communication mode)

	MB96610								
Pin Number	Pin Number USART Number								
7		SIN2							
8	USART2	SOT2							
9		SCK2							
20		SIN7_R							
19	USART7	SOT7_R							
18		SCK7_R							
22		SIN8_R							
21	USART8	SOT8_R							
23		SCK8_R							

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11. Interrupt Vector Table

Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to program	Description
0	3FC _H	CALLV0	No	-	CALLV instruction
1	3F8 _H	CALLV1	No	-	CALLV instruction
2	3F4 _H	CALLV2	No	-	CALLV instruction
3	3F0 _H	CALLV3	No	-	CALLV instruction
4	3EC _H	CALLV4	No	-	CALLV instruction
5	3E8 _H	CALLV5	No	-	CALLV instruction
6	3E4 _H	CALLV6	No	-	CALLV instruction
7	3E0 _H	CALLV7	No	-	CALLV instruction
8	3DC _H	RESET	No	-	Reset vector
9	3D8 _H	INT9	No	-	INT9 instruction
10	3D4 _H	EXCEPTION	No	-	Undefined instruction execution
11	3D0 _H	NMI	No	-	Non-Maskable Interrupt
12	3CC _H	DLY	No	12	Delayed Interrupt
13	3C8 _H	RC_TIMER	No	13	RC Clock Timer
14	3C4 _H	MC_TIMER	No	14	Main Clock Timer
15	3C0 _H	SC_TIMER	No	15	Sub Clock Timer
16	3ВС _н	LVDI	No	16	Low Voltage Detector
17	3B8 _H	EXTINT0	Yes	17	External Interrupt 0
18	3B4 _H	-	-	18	Reserved
19	3B0 _H	EXTINT2	Yes	19	External Interrupt 2
20	ЗАСн	EXTINT3	Yes	20	External Interrupt 3
21	3A8 _H	EXTINT4	Yes	21	External Interrupt 4
22	3A4 _H	-	-	22	Reserved
23	3A0 _H	-	-	23	Reserved
24	39C _H	EXTINT7	Yes	24	External Interrupt 7
25	398 _H	EXTINT8	Yes	25	External Interrupt 8
26	394 _H	EXTINT9	Yes	26	External Interrupt 9
27	390н	EXTINT10	Yes	27	External Interrupt 10
28	38C _H	EXTINT11	Yes	28	External Interrupt 11
29	388 _H	EXTINT12	Yes	29	External Interrupt 12
30	384 _H	EXTINT13	Yes	30	External Interrupt 13
31	380 _H	-	-	31	Reserved
32	37C _H	-	-	32	Reserved
33	378 _H	-	-	33	Reserved
34	374 _H	-	-	34	Reserved
35	370н	CAN2	No	35	CAN Controller 2
36	36C _H	-	-	36	Reserved
37	368н	-	-	37	Reserved
38	364 _H	PPG0	Yes	38	Programmable Pulse Generator 0
39	360 _H	PPG1	Yes	39	Programmable Pulse Generator 1

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Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to program	Description
40	35C _H	-	-	40	Reserved
41	358 _H	PPG3	Yes	41	Programmable Pulse Generator 3
42	354 _H	PPG4	Yes	42	Programmable Pulse Generator 4
43	350 _H	-	-	43	Reserved
44	34C _H	PPG6	Yes	44	Programmable Pulse Generator 6
45	348 _H	PPG7	Yes	45	Programmable Pulse Generator 7
46	344 _H	-	-	46	Reserved
47	340 _H	-	-	47	Reserved
48	33C _H	-	-	48	Reserved
49	338 _H	-	-	49	Reserved
50	334 _H	PPG12	Yes	50	Programmable Pulse Generator 12
51	330 _H	-	-	51	Reserved
52	32C _H	PPG14	Yes	52	Programmable Pulse Generator 14
53	328 _H	-	-	53	Reserved
54	324 _H	-	-	54	Reserved
55	320 _H	-	-	55	Reserved
56	31C _H	-	-	56	Reserved
57	318 _H	-	-	57	Reserved
58	314 _H	-	-	58	Reserved
59	310 _H	RLT1	Yes	59	Reload Timer 1
60	30C _H	-	-	60	Reserved
61	308 _H	RLT3	Yes	61	Reload Timer 3
62	304 _H	-	-	62	Reserved
63	300 _H	-	-	63	Reserved
64	2FC _H	RLT6	Yes	64	Reload Timer 6
65	2F8 _H	ICU0	Yes	65	Input Capture Unit 0
66	2F4 _H	ICU1	Yes	66	Input Capture Unit 1
67	2F0 _H	-	-	67	Reserved
68	2EC _H	-	-	68	Reserved
69	2E8 _H	ICU4	Yes	69	Input Capture Unit 4
70	2E4 _H	ICU5	Yes	70	Input Capture Unit 5
71	2E0 _H	ICU6	Yes	71	Input Capture Unit 6
72	2DC _H	-	-	72	Reserved
73	2D8 _H	-	-	73	Reserved
74	2D4 _H	ICU9	Yes	74	Input Capture Unit 9
75	2D0 _H	ICU10	Yes	75	Input Capture Unit 10
76	2CC _H	-	-	76	Reserved
77	2C8 _H	OCU0	Yes	77	Output Compare Unit 0
78	2C4 _H	OCU1	Yes	78	Output Compare Unit 1
79	2C0 _H	-	-	79	Reserved
80	2BC _H	-	-	80	Reserved

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Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to program	Description
81	2B8 _H	OCU4	Yes	81	Output Compare Unit 4
82	2B4 _H	-	-	82	Reserved
83	2B0 _H	OCU6	Yes	83	Output Compare Unit 6
84	2AC _H	OCU7	Yes	84	Output Compare Unit 7
85	2A8 _H	-	-	85	Reserved
86	2A4 _H	-	-	86	Reserved
87	2A0 _H	-	-	87	Reserved
88	29C _H	-	-	88	Reserved
89	298 _H	FRT0	Yes	89	Free-Running Timer 0
90	294 _H	FRT1	Yes	90	Free-Running Timer 1
91	290н	FRT2	Yes	91	Free-Running Timer 2
92	28C _H	FRT3	Yes	92	Free-Running Timer 3
93	288 _H	RTC0	No	93	Real Time Clock
94	284 _H	CAL0	No	94	Clock Calibration Unit
95	280 _H	-	-	95	Reserved
96	27C _H	-	-	96	Reserved
97	278 _H	-	-	97	Reserved
98	274 _H	ADC0	Yes	98	A/D Converter 0
99	270 _H	-	-	99	Reserved
100	26C _H	-	-	100	Reserved
101	268 _H	-	-	101	Reserved
102	264 _H	-	-	102	Reserved
103	260 _H	-	-	103	Reserved
104	25C _H	-	-	104	Reserved
105	258 _H	LINR2	Yes	105	LIN USART 2 RX
106	254 _H	LINT2	Yes	106	LIN USART 2 TX
107	250н	-	-	107	Reserved
108	24C _H	-	-	108	Reserved
109	248 _H	-	-	109	Reserved
110	244 _H	-	-	110	Reserved
111	240 _H	-	-	111	Reserved
112	23C _H	-	-	112	Reserved
113	238 _H	-	-	113	Reserved
114	234 _H	-	-	114	Reserved
115	230н	LINR7	Yes	115	LIN USART 7 RX
116	22C _H	LINT7	Yes	116	LIN USART 7 TX
117	228 _H	LINR8	Yes	117	LIN USART 8 RX
118	224 _H	LINT8	Yes	118	LIN USART 8 TX
119	220 _H	-	-	119	Reserved
120	21C _H	-	-	120	Reserved
121	218 _H	-	-	121	Reserved

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Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to program	Description
122	214 _H	-	-	122	Reserved
123	210 _H	-	-	123	Reserved
124	20C _H	-	-	124	Reserved
125	208 _H	-	-	125	Reserved
126	204 _H	-	-	126	Reserved
127	200 _H	-	-	127	Reserved
128	1FC _H	-	-	128	Reserved
129	1F8 _H	-	-	129	Reserved
130	1F4 _H	-	-	130	Reserved
131	1F0 _H	-	-	131	Reserved
132	1EC _H	-	-	132	Reserved
133	1E8 _H	FLASHA	Yes	133	Flash memory A interrupt
134	1E4 _H	-	-	134	Reserved
135	1E0 _H	-	-	135	Reserved
136	1DC _H	-	-	136	Reserved
137	1D8 _H	QPRC0	Yes	137	Quad Position/Revolution counter 0
138	1D4 _H	QPRC1	Yes	138	Quad Position/Revolution counter 1
139	1D0 _H	ADCRC0	No	139	A/D Converter 0 - Range Comparator
140	1CC _H	-	-	140	Reserved
141	1C8 _H	-	-	141	Reserved
142	1C4 _H	-	-	142	Reserved
143	1C0 _H	-	-	143	Reserved

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12. Handling Precautions

Any semiconductor devices have inherently a certain rate of failure. The possibility of failure is greatly affected by the conditions in which they are used (circuit conditions, environmental conditions, etc.). This page describes precautions that must be observed to minimize the chance of failure and to obtain higher reliability from your Cypress semiconductor devices.

12.1 Precautions for Product Design

This section describes precautions when designing electronic equipment using semiconductor devices.

■ Absolute Maximum Ratings

Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of certain established limits, called absolute maximum ratings. Do not exceed these ratings.

■ Recommended Operating Conditions

Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their sales representative beforehand.

■ Processing and Protection of Pins

These precautions must be followed when handling the pins which connect semiconductor devices to power supply and input/output functions.

1. Preventing Over-Voltage and Over-Current Conditions

Exposure to voltage or current levels in excess of maximum ratings at any pin is likely to cause deterioration within the device, and in extreme cases leads to permanent damage of the device. Try to prevent such overvoltage or over-current conditions at the design stage.

2. Protection of Output Pins

Shorting of output pins to supply pins or other output pins, or connection to large capacitance can cause large current flows. Such conditions if present for extended periods of time can damage the device. Therefore, avoid this type of connection.

Handling of Unused Input Pins

Unconnected input pins with very high impedance levels can adversely affect stability of operation. Such pins should be connected through an appropriate resistance to a power supply pin or ground pin.

■ Latch-up

Semiconductor devices are constructed by the formation of P-type and N-type areas on a substrate. When subjected to abnormally high voltages, internal parasitic PNPN junctions (called thyristor structures) may be formed, causing large current levels in excess of several hundred mA to flow continuously at the power supply pin. This condition is called latch-up.

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CAUTION:

The occurrence of latch-up not only causes loss of reliability in the semiconductor device, but can cause injury or damage from high heat, smoke or flame. To prevent this from happening, do the following:

- 1. Be sure that voltages applied to pins do not exceed the absolute maximum ratings. This should include attention to abnormal noise, surge levels, etc.
- 2. Be sure that abnormal current flows do not occur during the power-on sequence.
- Observance of Safety Regulations and Standards

Most countries in the world have established standards and regulations regarding safety, protection from electromagnetic interference, etc. Customers are requested to observe applicable regulations and standards in the design of products.

■ Fail-Safe Design

Any semiconductor devices have inherently a certain rate of failure. You must protect against injury, damage or loss from such failures by incorporating safety design measures into your facility and equipment such as redundancy, fire protection, and prevention of over-current levels and other abnormal operating conditions.

■ Precautions Related to Usage of Devices

Cypress semiconductor devices are intended for use in standard applications (computers, office automation and other office equipment, industrial, communications, and measurement equipment, personal or household devices, etc.).

CAUTION:

Customers considering the use of our products in special applications where failure or abnormal operation may directly affect human lives or cause physical injury or property damage, or where extremely high levels of reliability are demanded (such as aerospace systems, atomic energy controls, sea floor repeaters, vehicle operating controls, medical devices for life support, etc.) are requested to consult with sales representatives before such use. The company will not be responsible for damages arising from such use without prior approval.

12.2 Precautions for Package Mounting

Package mounting may be either lead insertion type or surface mount type. In either case, for heat resistance during soldering, you should only mount under Cypress's recommended conditions. For detailed information about mount conditions, contact your sales representative.

■ Lead Insertion Type

Mounting of lead insertion type packages onto printed circuit boards may be done by two methods: direct soldering on the board, or mounting by using a socket.

Direct mounting onto boards normally involves processes for inserting leads into through-holes on the board and using the flow soldering (wave soldering) method of applying liquid solder. In this case, the soldering process usually causes leads to be subjected to thermal stress in excess of the absolute ratings for storage temperature. Mounting processes should conform to Cypress recommended mounting conditions.

If socket mounting is used, differences in surface treatment of the socket contacts and IC lead surfaces can lead to contact deterioration after long periods. For this reason it is recommended that the surface treatment of socket contacts and IC leads be verified before mounting.

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■ Surface Mount Type

Surface mount packaging has longer and thinner leads than lead-insertion packaging, and therefore leads are more easily deformed or bent. The use of packages with higher pin counts and narrower pin pitch results in increased susceptibility to open connections caused by deformed pins, or shorting due to solder bridges.

You must use appropriate mounting techniques. Cypress recommends the solder reflow method, and has established a ranking of mounting conditions for each product. Users are advised to mount packages in accordance with Cypress ranking of recommended conditions.

■ Lead-Free Packaging

CAUTION:

When ball grid array (BGA) packages with Sn-Ag-Cu balls are mounted using Sn-Pb eutectic soldering, junction strength may be reduced under some conditions of use.

Storage of Semiconductor Devices

Because plastic chip packages are formed from plastic resins, exposure to natural environmental conditions will cause absorption of moisture. During mounting, the application of heat to a package that has absorbed moisture can cause surfaces to peel, reducing moisture resistance and causing packages to crack. To prevent, do the following:

- Avoid exposure to rapid temperature changes, which cause moisture to condense inside the product. Store products in locations where temperature changes are slight.
- 2. Use dry boxes for product storage. Products should be stored below 70% relative humidity, and at temperatures between 5°C and 30°C.When you open Dry Package that recommends humidity 40% to 70% relative humidity.
- 3. When necessary, Cypress packages semiconductor devices in highly moisture-resistant aluminum laminate bags, with a silica gel desiccant. Devices should be sealed in their aluminum laminate bags for storage.
- 4. Avoid storing packages where they are exposed to corrosive gases or high levels of dust.

■ Baking

Packages that have absorbed moisture may be de-moisturized by baking (heat drying). Follow the Cypress recommended conditions for baking.

Condition: 125°C/24 h

■ Static Electricity

Because semiconductor devices are particularly susceptible to damage by static electricity, you must take the following precautions:

- 1. Maintain relative humidity in the working environment between 40% and 70%. Use of an apparatus for ion generation may be needed to remove electricity.
- Electrically ground all conveyors, solder vessels, soldering irons and peripheral equipment.
- Eliminate static body electricity by the use of rings or bracelets connected to ground through high resistance (on the level of 1 MΩ). Wearing of conductive clothing and shoes, use of conductive floor mats and other measures to minimize shock loads is recommended.
- 4. Ground all fixtures and instruments, or protect with anti-static measures.
- 5. Avoid the use of styro foam or other highly static-prone materials for storage of completed board assemblies.

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12.3 Precautions for Use Environment

Reliability of semiconductor devices depends on ambient temperature and other conditions as described above.

For reliable performance, do the following:

1. Humidity

Prolonged use in high humidity can lead to leakage in devices as well as printed circuit boards. If high humidity levels are anticipated, consider anti-humidity processing.

2. Discharge of Static Electricity

When high-voltage charges exist close to semiconductor devices, discharges can cause abnormal operation. In such cases, use anti-static measures or processing to prevent discharges.

3. Corrosive Gases, Dust, or Oil

Exposure to corrosive gases or contact with dust or oil may lead to chemical reactions that will adversely affect the device. If you use devices in such conditions, consider ways to prevent such exposure or to protect the devices.

4. Radiation, Including Cosmic Radiation

Most devices are not designed for environments involving exposure to radiation or cosmic radiation. Users should provide shielding as appropriate.

5. Smoke, Flame

CAUTION:

Plastic molded devices are flammable, and therefore should not be used near combustible substances. If devices begin to smoke or burn, there is danger of the release of toxic gases.

Customers considering the use of Cypress products in other special environmental conditions should consult with sales representatives.

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13. Handling Devices

Special care is required for the following when handling the device:

- Latch-up prevention
- Unused pins handling
- External clock usage
- Notes on PLL clock mode operation
- Power supply pins (Vcc/Vss)
- Crystal oscillator and ceramic resonator circuit
- Turn on sequence of power supply to A/D converter and analog inputs
- Pin handling when not using the A/D converter
- Notes on Power-on
- Stabilization of power supply voltage
- Serial communication
- Mode Pin (MD)

13.1 Latch-up prevention

CMOS IC chips may suffer latch-up under the following conditions:

- A voltage higher than V_{CC} or lower than V_{SS} is applied to an input or output pin.
- A voltage higher than the rated voltage is applied between Vcc pins and Vss pins.
- The AV_{CC} power supply is applied before the V_{CC} voltage.

Latch-up may increase the power supply current dramatically, causing thermal damages to the device.

For the same reason, extra care is required to not let the analog power-supply voltage (AV_{CC}, AVRH) exceed the digital power-supply voltage.

13.2 Unused pins handling

Unused input pins can be left open when the input is disabled (corresponding bit of Port Input Enable register PIER = 0).

Leaving unused input pins open when the input is enabled may result in misbehavior and possible permanent damage of the device. To prevent latch-up, they must therefore be pulled up or pulled down through resistors which should be more than $2k\Omega$.

Unused bidirectional pins can be set either to the output state and be then left open, or to the input state with either input disabled or external pull-up/pull-down resistor as described above.

13.3 External clock usage

The permitted frequency range of an external clock depends on the oscillator type and configuration.

See

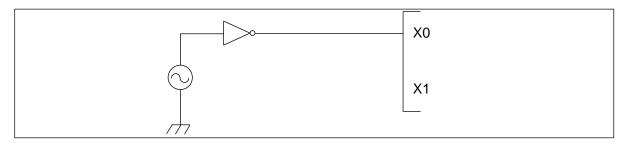
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AC Characteristics for detailed modes and frequency limits. Single and opposite phase external clocks must be connected as follows:

13.3.1 Single phase external clock for Main oscillator

When using a single phase external clock for the Main oscillator, X0 pin must be driven and X1 pin left open. And supply 1.8V power to the external clock.

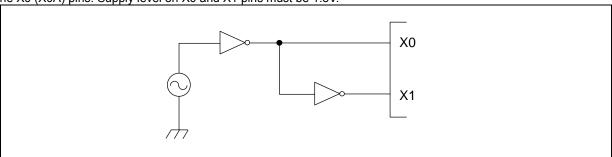


13.3.2 Single phase external clock for Sub oscillator

When using a single phase external clock for the Sub oscillator, "External clock mode" must be selected and X0A/P04_0 pin must be driven. X1A/P04_1 pin can be configured as GPIO.

13.3.3 Opposite phase external clock

When using an opposite phase external clock, X1 (X1A) pins must be supplied with a clock signal which has the opposite phase to the X0 (X0A) pins. Supply level on X0 and X1 pins must be 1.8V.



13.4 Notes on PLL clock mode operation

If the microcontroller is operated with PLL clock mode and no external oscillator is operating or no external clock is supplied, the microcontroller attempts to work with the free oscillating PLL. Performance of this operation, however, cannot be guaranteed.

13.5 Power supply pins (Vcc/Vss)

It is required that all V_{CC} -level as well as all V_{SS} -level power supply pins are at the same potential. If there is more than one V_{CC} or V_{SS} level, the device may operate incorrectly or be damaged even within the guaranteed operating range.

Vcc and Vss pins must be connected to the device from the power supply with lowest possible impedance.

The smoothing capacitor at Vcc pin must use the one of a capacity value that is larger than Cs.

Besides this, as a measure against power supply noise, it is required to connect a bypass capacitor of about $0.1\mu F$ between Vcc and Vss pins as close as possible to Vcc and Vss pins.

13.6 Crystal oscillator and ceramic resonator circuit

Noise at X0, X1 pins or X0A, X1A pins might cause abnormal operation. It is required to provide bypass capacitors with shortest possible distance to X0, X1 pins and X0A, X1A pins, crystal oscillator (or ceramic resonator) and ground lines, and, to the utmost effort, that the lines of oscillation circuit do not cross the lines of other circuits.

It is highly recommended to provide a printed circuit board art work surrounding X0, X1 pins and X0A, X1A pins with a ground area for stabilizing the operation.

It is highly recommended to evaluate the quartz/MCU or resonator/MCU system at the quartz or resonator manufacturer, especially when using low-Q resonators at higher frequencies.

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13.7 Turn on sequence of power supply to A/D converter and analog inputs

It is required to turn the A/D converter power supply (AVcc, AVRH) and analog inputs (ANn) on after turning the digital power supply (Vcc) on.

It is also required to turn the digital power off after turning the A/D converter supply and analog inputs off. In this case, AVRH must not exceed AVcc Input voltage for ports shared with analog input ports also must not exceed AVcc (turning the analog and digital power supplies simultaneously on or off is acceptable)

13.8 Pin handling when not using the A/D converter

If the A/D converter is not used, the power supply pins for A/D converter should be connected such as $AV_{CC} = V_{CC} AV_{SS} = AVRH = V_{SS}$.

13.9 Notes on Power-on

To prevent malfunction of the internal voltage regulator, supply voltage profile while turning the power supply on should be slower than $50\mu s$ from 0.2V to 2.7V.

13.10Stabilization of power supply voltage

If the power supply voltage varies acutely even within the operation safety range of the V_{CC} power supply voltage, a malfunction may occur. The V_{CC} power supply voltage must therefore be stabilized. As stabilization guidelines, the power supply voltage must be stabilized in such a way that V_{CC} ripple fluctuations (peak to peak value) in the commercial frequencies (50Hz to 60Hz) fall within 10% of the standard V_{CC} power supply voltage and the transient fluctuation rate becomes $0.1V/\mu s$ or less in instantaneous fluctuation for power supply switching.

13.11 Serial communication

There is a possibility to receive wrong data due to noise or other causes on the serial communication.

Therefore, design a printed circuit board so as to avoid noise.

Consider receiving of wrong data when designing the system. For example apply a checksum and retransmit the data if an error occurs.

13.12Mode Pin (MD)

Connect the mode pin directly to Vcc or Vss pin. To prevent the device unintentionally entering test mode due to noise, lay out the printed circuit board so as to minimize the distance from the mode pin to Vcc or Vss pin and provide a low-impedance connection.

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14. Electrical Characteristics

14.1 Absolute Maximum Ratings

D 1			R	ating			
Parameter	Symbol	Condition	Min	Max	Unit	Remarks	
Power supply voltage ^[1]	V _{cc}	-	V _{SS} - 0.3	V _{SS} + 6.0	V		
Analog power supply voltage ^[1]	AV _{CC}	-	V _{SS} - 0.3	V _{SS} + 6.0	V	$V_{CC} = AV_{CC}^{[2]}$	
Analog reference voltage ^[1]	AVRH	-	V _{SS} - 0.3	V _{SS} + 6.0	V	AV _{CC} ≥ AVRH, AVRH ≥ AV _{SS}	
Input voltage[1]	Vı	-	V _{SS} - 0.3	V _{SS} + 6.0	V	$V_1 \le V_{CC} + 0.3V^{[3]}$	
Output voltage[1]	Vo	=	V _{SS} - 0.3	V _{SS} + 6.0	V	$V_0 \le V_{CC} + 0.3V^{[3]}$	
Maximum Clamp Current	I _{CLAMP}	-	-4.0	+4.0	mA	Applicable to general purpose I/O pins [4]	
Total Maximum Clamp Current	Σ I _{CLAMP}	-	-	13	mA	Applicable to general purpose I/O pins [4]	
"L" level maximum output current	I _{OL}	-	-	15	mA		
"L" level average output current	I _{OLAV}	-	-	4	mA		
"L" level maximum overall output current	ΣI _{OL}	-	-	32	mA		
"L" level average overall output current	ΣI _{OLAV}	-	-	16	mA		
"H" level maximum output current	I _{OH}	-	-	-15	mA		
"H" level average output current	I _{OHAV}	-	-	-4	mA		
"H" level maximum overall output current	Σι _{οн}	-	-	-32	mA		
"H" level average overall output current	ΣI _{OHAV}	-	-	-16	mA		
Power consumption ^[5]	P _D	T _A = +125°C	-	284 ^[6]	mW		
Operating ambient temperature	T _A	-	-40	+125 ^[7]	°C		
Storage temperature	T _{STG}	-	-55	+150	°C		

[1]: This parameter is based on V_{SS} = AV_{SS} = 0V.

[2]: AV_{CC} and V_{CC} must be set to the same voltage. It is required that AV_{CC} does not exceed V_{CC} and that the voltage at the analog inputs does not exceed AV_{CC} when the power is switched on.

[3]: V_I and V_O should not exceed V_{CC} + 0.3V. V_I should also not exceed the specified ratings. However if the maximum current to/from an input is limited by some means with external components, the I_{CLAMP} rating supersedes the V_I rating. Input/Output voltages of standard ports depend on V_{CC} .

[4]:

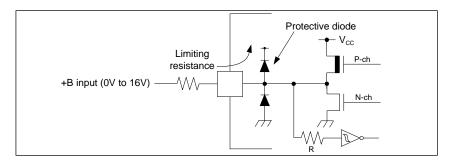
- Applicable to all general purpose I/O pins (Pnn_m).
- Use within recommended operating conditions.
- Use at DC voltage (current).
- The +B signal should always be applied a limiting resistance placed between the +B signal and the microcontroller.
- The value of the limiting resistance should be set so that when the +B signal is applied the input current to microcontroller pin does not exceed rated values, either instantaneously or for prolonged periods.

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- Note that when the microcontroller drive current is low, such as in the power saving modes, the +B input potential may pass through the protective diode and increase the potential at the VCC pin, and this may affect other devices.
- Note that if a +B signal is input when the microcontroller power supply is off (not fixed at 0V), the power supply is provided from the pins, so that incomplete operation may result.
- Note that if the +B input is applied during power-on, the power supply is provided from the pins and the resulting supply voltage may not be sufficient to operate the Power reset.
- The DEBUG I/F pin has only a protective diode against VSS. Hence it is only permitted to input a negative clamping current (4mA). For protection against positive input voltages, use an external clamping diode which limits the input voltage to maximum 6.0V.

Sample recommended circuits:



[5]: The maximum permitted power dissipation depends on the ambient temperature, the air flow velocity and the thermal conductance of the package on the PCB.

The actual power dissipation depends on the customer application and can be calculated as follows:

 $P_D = P_{IO} + P_{INT}$

 $P_{IO} = \Sigma (V_{OL} \times I_{OL} + V_{OH} \times I_{OH})$ (I/O load power dissipation, sum is performed on all I/O ports)

 $P_{INT} = V_{CC} \times (I_{CC} + I_A)$ (internal power dissipation)

 I_{CC} is the total core current consumption into V_{CC} as described in the "DC characteristics" and depends on the selected operation mode and clock frequency and the usage of functions like Flash programming.

IA is the analog current consumption into AVCC.

- [6]: Worst case value for a package mounted on single layer PCB at specified TA without air flow.
- [7]: Write/erase to a large sector in flash memory is warranted with T_A ≤ + 105°C.

WARNING:

Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

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14.2 Recommended Operating Conditions

 $(V_{SS} = AV_{SS} = 0V)$

D	0	Value			1114	Domesto
Parameter	Symbol	Min	Тур	Max	Unit	Remarks
Power supply voltage	V _{CC} , AV _{CC}	2.7	-	5.5	V	
Fower supply voltage	VCC, AVCC	2.0	-	5.5	V	Maintains RAM data in stop mode
Smoothing capacitor at C pin	Cs	0.5	1.0 to 3.9	4.7	μF	1.0µF (Allowance within ± 50%) 3.9µF (Allowance within ± 20%) Please use the ceramic capacitor or the capacitor of the frequency response of this level. The smoothing capacitor at V _{CC} must use the one of a capacity value that is larger than C _S .

WARNING:

The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.

Always use semiconductor devices within their recommended operating condition ranges. Operation outside these ranges may adversely affect reliability and could result in device failure. No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their representatives beforehand.

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14.3 DC Characteristics

14.3.1 Current Rating

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C)$

CC = AVCC = 2.7V		Pin			Value			
Parameter	Symbol	name	Conditions	Min	Тур	Max	Unit	Remarks
			PLL Run mode with CLKS1/2 =	-	25	-	mA	T _A = +25°C
	I _{CCPLL}		CLKB = CLKP1/2 = 32MHz Flash 0 wait (CLKRC and CLKSC stopped)	-	-	34	mA	T _A = +105°C
			(CERRO and CERSO Stopped)	-	-	35	mA	T _A = +125°C
			Main Run mode with CLKS1/2 = CLKB = CLKP1/2 = 4MHz	-	3.5	-	mA	T _A = +25°C
	I _{CCMAIN}		Flash 0 wait (CLKPLL, CLKSC and CLKRC	-	-	7.5	mA	T _A = +105°C
			stopped)	-	-	8.5	mA	T _A = +125°C
			RC Run mode with CLKS1/2 = CLKB = CLKP1/2 = CLKRC = 2MHz Flash 0 wait (CLKMC, CLKPLL and CLKSC stopped)	-	1.7	-	mA	T _A = +25°C
Power supply current in Run modes ^[1]	I _{CCRCH}	Vcc		-	-	5.5	mA	T _A = +105°C
				-	=	6.5	mA	T _A = +125°C
			RC Run mode with CLKS1/2 = CLKB = CLKP1/2 = CLKRC = 100kHz Flash 0 wait (CLKMC, CLKPLL and CLKSC	-	0.15	-	mA	T _A = +25°C
	I _{CCRCL}			-	-	3.2	mA	T _A = +105°C
			stopped)	-	-	4.2	mA	T _A = +125°C
			Sub Run mode with CLKS1/2 = CLKB = CLKP1/2 = 32kHz Flash 0 wait (CLKMC, CLKPLL and CLKRC	-	0.1	-	mA	T _A = +25°C
	I _{CCSUB}			-	-	3	mA	T _A = +105°C
			stopped)	-	-	4	mA	T _A = +125°C

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		Pin	Conditions		Value		Τ	Remarks
Parameter	Symbol	name		Min	Тур	Max	Unit	
			PLL Sleep mode with	-	6.5	-	mA	T _A = +25°C
	I _{CCSPLL}		CLKS1/2 = CLKP1/2 = 32MHz (CLKRC and CLKSC stopped)	-	-	13	mA	T _A = +105°C
			(CENNO and CENGO stopped)	-	-	14	mA	T _A = +125°C
			Main Sleep mode with	-	0.9	-	mA	T _A = +25°C
	I _{CCSMAIN}		CLKS1/2 = CLKP1/2 = 4MHz, SMCR:LPMSS = 0	-	-	4	mA	T _A = +105°C
			(CLKPLL, CLKRC and CLKSC stopped)	-	-	5	mA	T _A = +125°C
	I _{CCSRCH} Vcc		RC Sleep mode with CLKS1/2 = CLKP1/2 = CLKRC = 2MHz, SMCR:LPMSS = 0 (CLKMC, CLKPLL and CLKSC stopped)	-	0.5	-	mA	T _A = +25°C
Power supply current in Sleep modes ^[1]		Vcc		-	-	3.5	mA	T _A = +105°C
				-	-	4.5	mA	T _A = +125°C
	I _{CCSRCL}		RC Sleep mode with CLKS1/2 =	-	0.06	-	mA	T _A = +25°C
			CLKP1/2 = CLKRC = 100kHz (CLKMC, CLKPLL and CLKSC	-	-	2.7	mA	T _A = +105°C
			stopped)	-	-	3.7	mA	T _A = +125°C
			Sub Sleep mode with CLKS1/2 = CLKP1/2 = 32kHz, (CLKMC, CLKPLL and CLKRC stopped)	-	0.04	-	mA	T _A = +25°C
	Iccssuв			-	-	2.5	mA	T _A = +105°C
				-	-	3.5	mA	T _A = +125°C

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B	0	Pin	0		Value		1114	Domonika
Parameter	Symbol	name	Conditions	Min	Тур	Max	Unit	Remarks
			511 5 11 11 11 11 11 11 11 11 11 11 11 11 11	-	1800	2245	μΑ	T _A = +25°C
	I _{CCTPLL}		PLL Timer mode with CLKPLL = 32MHz (CLKRC and CLKSC stopped)	-	-	3165	μА	T _A = +105°C
			Сюрром	-	-	3975	μΑ	T _A = +125°C
			Main Timer mode with	-	285	325	μΑ	T _A = +25°C
	I _{CCTMAIN}		CLKMC = 4MHz, SMCR:LPMSS = 0	-	-	1085	μΑ	T _A = +105°C
			(CLKPLL, CLKRC and CLKSC stopped)	-	-	1930	μΑ	T _A = +125°C
_			RC Timer mode with	-	160	210	μА	T _A = +25°C
Power supply current in	I _{CCTRCH}	Vcc	CLKRC = 2MHz,	-	-	1025	μΑ	T _A = +105°C
Timer modes ^[2]			SMCR:LPMSS = 0 (CLKPLL, CLKMC and CLKSC stopped)	-	-	1840	μΑ	T _A = +125°C
			RC Timer mode with CLKRC = 100kHz (CLKPLL, CLKMC and CLKSC stopped)	-	35	75	μΑ	T _A = +25°C
	I _{CCTRCL}			-	-	855	μΑ	T _A = +105°C
				-	-	1640	μΑ	T _A = +125°C
			Sub Timer mode with	-	25	65	μΑ	T _A = +25°C
	I _{CCTSUB}		CLKSC = 32kHz (CLKMC,	-	-	830	μΑ	T _A = +105°C
			CLKPLL and CLKRC stopped)	-	-	1620	μΑ	T _A = +125°C
Power supply				-	20	55	μA	T _A = +25°C
current in Stop	I _{CCH}		-	-	-	825	μA	T _A = +105°C
mode ^[3]				-	-	1615	μΑ	T _A = +125°C
Flash Power Down current	I _{CCFLASHPD}		-	-	36	70	μΑ	
Power supply current		Vcc		-	5	-	μΑ	T _A = +25°C
for active Low Voltage detector ^[4]	I _{CCLVD}		Low voltage detector enabled	-	-	12.5	μА	T _A = +125°C
Flash Write/				-	12.5	-	mA	T _A = +25°C
Erase current ^[5]	I _{CCFLASH}		-	-	-	20	mA	T _A = +125°C

^{[1]:} The power supply current is measured with a 4MHz external clock connected to the Main oscillator and a 32kHz external clock connected to the Sub oscillator. See chapter "Standby mode and voltage regulator control circuit" of the Hardware Manual for further details about voltage regulator control. Current for "On Chip Debugger" part is not included. Power supply current in Run mode does not include Flash Write / Erase current.

[2]: The power supply current in Timer mode is the value when Flash is in Power-down / reset mode.

When Flash is not in Power-down / reset mode, IccFlashpd must be added to the Power supply current.

The power supply current is measured with a 4MHz external clock connected to the Main oscillator and a 32kHz external clock connected to the Sub oscillator. The current for "On Chip Debugger" part is not included.

[3]: The power supply current in Stop mode is the value when Flash is in Power-down / reset mode.

When Flash is not in Power-down / reset mode, ICCFLASHPD must be added to the Power supply current.

- [4]: When low voltage detector is enabled, ICCLVD must be added to Power supply current.
- [5]: When Flash Write / Erase program is executed, IccFLASH must be added to Power supply current.

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14.3.2 Pin Characteristics

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C)$

			0 !!!		Value			
Parameter	Symbol	Pin name	Conditions	Min	Тур	Max	Unit	Remarks
			-	V _{CC} ×0.7	-	V _{CC} + 0.3	V	CMOS Hysteresis input
	V _{IH}	Port inputs Pnn_m	-	V _{CC} ×0.8	-	V _{CC} + 0.3	V	AUTOMOTIVE Hysteresis input
"H" level input	V _{IHX0S}	X0	External clock in "Fast Clock Input mode"	VD×0.8	-	VD	V	VD=1.8V±0.15V
voltage	V _{IHX0AS}	X0A	External clock in "Oscillation mode"	V _{CC} ×0.8	-	V _{CC} + 0.3	٧	
	V_{IHR}	RSTX	-	V _{CC} ×0.8	-	V _{CC} + 0.3	V	CMOS Hysteresis input
	V_{IHM}	MD	-	V _{CC} - 0.3	-	V _{CC} + 0.3	V	CMOS Hysteresis input
	V_{IHD}	DEBUG I/F	-	2.0	-	V _{CC} + 0.3	V	TTL Input
		David Samuela	=	V _{SS} - 0.3	-	V _{CC} ×0.3	V	CMOS Hysteresis input
	V _{IL}	Port inputs Pnn_m	-	V _{SS} - 0.3	-	V _{CC} ×0.5	V	AUTOMOTIVE Hysteresis input
"L" level input voltage	V _{ILX0S}	X0	External clock in "Fast Clock Input mode"	V _{SS}	-	VD×0.2	V	VD=1.8V±0.15V
	V _{ILX0AS}	X0A	External clock in "Oscillation mode"	V _{SS} - 0.3	-	V _{CC} ×0.2	٧	
	V _{ILR}	RSTX	-	V _{SS} - 0.3	-	V _{CC} ×0.2	V	CMOS Hysteresis input
	V _{ILM}	MD	-	V _{SS} - 0.3	-	V _{SS} + 0.3	V	CMOS Hysteresis input
	V _{ILD}	DEBUG I/F	-	V _{SS} - 0.3	-	0.8	V	TTL Input
"H" level output voltage	V _{OH4}	4mA type	$4.5V \le V_{CC} \le 5.5V$ $I_{OH} = -4mA$ $2.7V \le V_{CC} < 4.5V$ $I_{OH} = -1.5mA$	V _{cc} - 0.5	-	Vcc	V	
"L" level	V _{OL4}	4mA type	$4.5V \le V_{CC} \le 5.5V$ $I_{OL} = +4mA$ $2.7V \le V_{CC} < 4.5V$ $I_{OL} = +1.7mA$	-	-	0.4	V	
	V _{OLD}	DEBUG I/F	$V_{CC} = 2.7V$ $I_{OL} = +25mA$	0	-	0.25	٧	
Input leak current	I _{IL}	Pnn_m	$V_{SS} < V_I < V_{CC}$ $AV_{SS} < V_I < AV_{CC}$, AVRH	- 1	-	+ 1	μА	
Pull-up resistance value	R _{PU}	Pnn_m	V _{CC} = 5.0V ±10%	25	50	100	kΩ	
Input capacitance	C _{IN}	Other than C, Vcc, Vss, AVcc, AVss, AVRH	-	-	5	15	pF	

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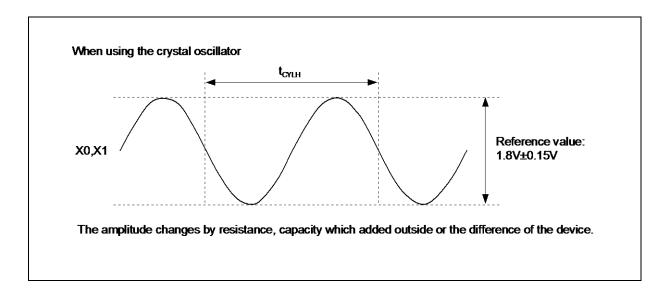


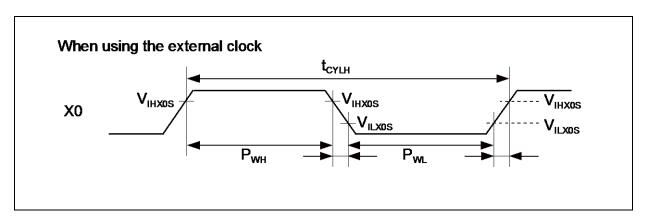
14.4 AC Characteristics

14.4.1 Main Clock Input Characteristics

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, VD=1.8V\pm0.15V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C)$

		Pin		Value			Barranta	
Parameter	Symbol	name	Min	Тур	Max	Unit	Remarks	
	fc	X0, X1	4	-	8	MHz	When using a crystal oscillator, PLL off	
Input frequency			-	ı	8	MHz	When using an opposite phase external clock, PLL off	
4 - 8 N		MHz	When using a crystal oscillator or opposite phase external clock, PLL on					
Input from one			-	-	8	MHz	When using a single phase external clock in "Fast Clock Input mode", PLL off	
Input frequency	f _{FCI}	X0	4	ı	8	MHz	When using a single phase external clock in "Fast Clock Input mode", PLL on	
Input clock cycle	t _{CYLH}	-	125	-	-	ns		
Input clock pulse width	P _{WH} , P _{WL}	-	55	-	-	ns		





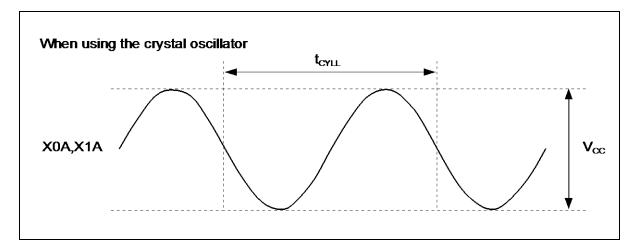
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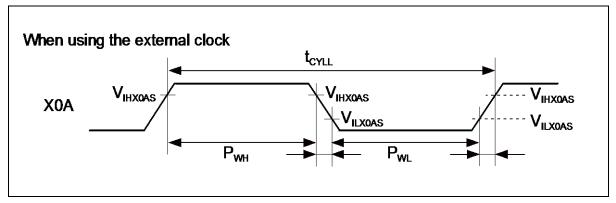


14.4.2 Sub Clock Input Characteristics

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C)$

Danamatan	0	Pin	Conditions		Value		Unit	Domonto	
Parameter	Symbol	name	Conditions	Min	Тур	Max	Unit	Remarks	
		\/O.A	-	-	32.768	-	kHz	When using an oscillation circuit	
Input frequency	nput frequency f _{CL}	X0A, X1A	-	-	-	100	kHz	When using an opposite phase external clock	
		X0A	-	-	-	50	kHz	When using a single phase external clock	
Input clock cycle	t _{CYLL}	-	-	10	-	-	μs		
Input clock pulse width	-	-	P _{WH} /t _{CYLL} , P _{WL} /t _{CYLL}	30	-	70	%		





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14.4.3 Built-in RC Oscillation Characteristics

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C)$

D	0		Value		1114	Domonto	
Parameter	Symbol	Min	Тур	Max	Unit	Remarks	
Clock frequency	f _{RC}	50	100	200	kHz	When using slow frequency of RC oscillator	
Glook frequency	TRC	1	2	4	MHz	When using fast frequency of RC oscillator	
		80	160	320	μs	When using slow frequency of RC oscillator (16 RC clock cycles)	
RC clock stabilization time	t _{RCSTAB}	64	128	256	μS	When using fast frequency of RC oscillator (256 RC clock cycles)	

14.4.4 Internal Clock Timing

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C)$

Danamatan	Oh. al	Va	Unit		
Parameter	Symbol	Min	Max	Unit	
Internal System clock frequency (CLKS1 and CLKS2)	f _{CLKS1} , f _{CLKS2}	1	54	MHz	
Internal CPU clock frequency (CLKB), Internal peripheral clock frequency (CLKP1)	f _{CLKB} , f _{CLKP1}	-	32	MHz	
Internal peripheral clock frequency (CLKP2)	f _{CLKP2}	-	32	MHz	

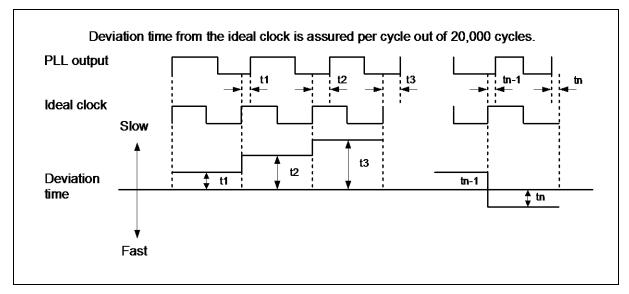
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14.4.5 Operating Conditions of PLL

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C)$

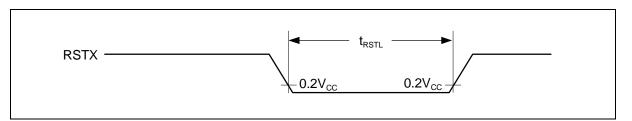
Danisation	Symbol	Value			1114	Remarks	
Parameter	Symbol	Min	Тур	Max	Unit	Remarks	
PLL oscillation stabilization wait time	t _{LOCK}	1	-	4	ms	For CLKMC = 4MHz	
PLL input clock frequency	f _{PLLI}	4	-	8	MHz		
PLL oscillation clock frequency	f _{CLKVCO}	56	-	108	MHz	Permitted VCO output frequency of PLL (CLKVCO)	
PLL phase jitter	t _{PSKEW}	-5	1	+5	ns	For CLKMC (PLL input clock) ≥ 4MHz	



14.4.6 Reset Input

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40°C to + 125°C)

Parameter	Symbol	Pin name	Va	Unit		
Parameter	Symbol	Pili liaille	Min	Max		
Reset input time	•	RSTX	10	-	μs	
Rejection of reset input time	^T RSTL	NOIN	1	-	μs	



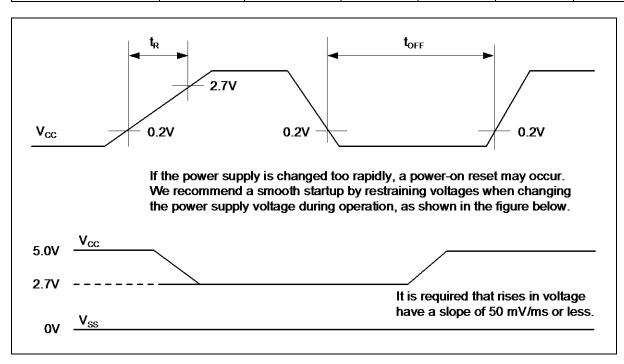
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14.4.7 Power-on Reset Timing

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C)$

B	0	Dia		Value		11-24	
Parameter	Symbol	Pin name	Min	Тур	Max	Unit	
Power on rise time	t _R	Vcc	0.05	-	30	ms	
Power off time	t _{OFF}	Vcc	1	-	-	ms	



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14.4.8 USART Timing

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C, C_L = 50pF)$

Parameter	Symbol	Pin name	Conditions	4.5V ≤ V _{CC} <	5.5V	2.7V ≤ V _{CC}	<4.5V	Uni
Farameter	Symbol	Fill Haille	Conditions	Min	Max	Min	Max	t
Serial clock cycle time	t _{SCYC}	SCKn		4tclkP1	-	4tclkP1	-	ns
SCK ↓ →SOT delay time	t _{SLOVI}	SCKn, SOTn		- 20	+ 20	- 30	+ 30	ns
SOT → SCK ↑ delay time	t _{OVSHI}	SCKn, SOTn	Internal shift clock	N×t _{CLKP1} — 20*	-	N×t _{CLKP1} -30*	-	ns
SIN → SCK ↑ setup time	t _{IVSHI}	SCKn, SINn	mode	tclkp1+ 45	-	tclkp1 + 55	-	ns
$SCK \uparrow \rightarrow SIN \text{ hold time}$	t _{SHIXI}	SCKn, SINn		0	-	0	-	ns
Serial clock "L" pulse width	t _{SLSH}	SCKn		t _{CLKP1} + 10	-	tclkp1 + 10	-	ns
Serial clock "H" pulse width	t _{SHSL}	SCKn		t _{CLKP1} + 10	-	t _{CLKP1} + 10	-	ns
$SCK\downarrow \to SOT$ delay time	t _{SLOVE}	SCKn, SOTn	External	-	2t _{CLKP1} + 45	-	2t _{CLKP1} + 55	ns
SIN → SCK ↑ setup time	t _{IVSHE}	SCKn, SINn	shift clock mode	tclkp1/2+ 10	-	t _{CLKP1} /2 + 10	-	ns
$SCK \uparrow \rightarrow SIN \text{ hold time}$	t _{SHIXE}	SCKn, SINn		tclkp1+ 10	-	tclkp1 + 10	-	ns
SCK fall time	t _F	SCKn		-	20	-	20	ns
SCK rise time	t _R	SCKn		-	20	-	20	ns

Notes:

- AC characteristic in CLK synchronized mode
- C_L is he load capacity value of pins when testing.
- Depending on the used machine clock frequency, the maximum possible baud rate can be limited by some parameters.
 These parameters are shown in "MB96600 series HARDWARE MANUAL".
- tclkP1 indicates the peripheral clock 1 (CLKP1), Unit: ns
 These characteristics only guarantee the same relocate port number.

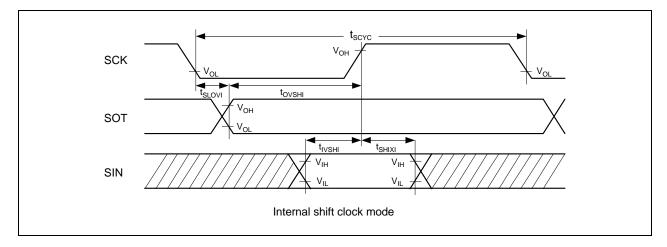
For example, the combination of SCKn and SOTn_R is not guaranteed.

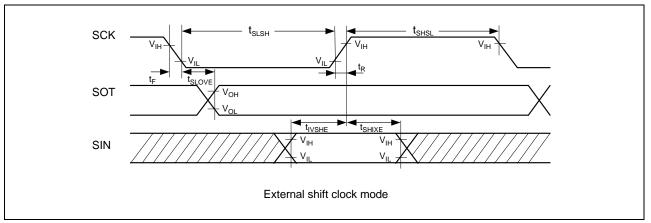
- *: Parameter N depends on tscyc and can be calculated as follows:
- If $t_{SCYC} = 2 \times k \times t_{CLKP1}$, then N = k, where k is an integer > 2
- If $t_{SCYC} = (2 \times k + 1) \times t_{CLKP1}$, then N = k + 1, where k is an integer > 1 Examples:

tscyc	N
4 ×tclkp1	2
5 xt _{CLKP1} , 6 xt _{CLKP1}	3
7 xtclkp1, 8 xtclkp1	4

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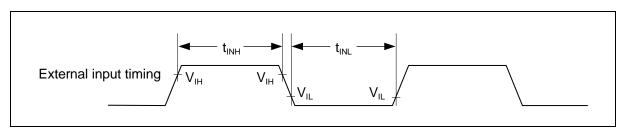


14.4.9 External Input Timing

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C)$

D	0	Dia	Value		1114	Remarks	
Parameter	Symbol	Pin name	Min	Max	Unit		
		Pnn_m				General Purpose I/O	
		ADTG_R				A/D Converter trigger input	
		TINn	TTGn 2t _{CLKP1} +200 (t _{CLKP1} =1/f _{CLKP1})*			Reload Timer	
		TTGn		-	ns	PPG trigger input	
Input pulse		INn				Input Capture	
width	t _{INH} , t _{INL}	AINn, BINn, ZINn				Quadrature Position/Revolution Counter	
		INTn, INTn_R, INTn_R1	200	-	ns	External Interrupt	
		NMI	1			Non-Maskable Interrupt	

^{*:} tclkp1 indicates the peripheral clock1 (CLKP1) cycle time except stop when in stop mode.



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14.5 A/D Converter

14.5.1 Electrical Characteristics for the A/D Converter

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } +125^{\circ}C)$

D	Value		Value		1114	Demonder	
Parameter	Symbol	Pin name	Min	Тур	Max	Unit	Remarks
Resolution	-	-	-	-	10	bit	
Total error	-	-	- 3.0	-	+ 3.0	LSB	
Nonlinearity error	-	-	- 2.5	-	+ 2.5	LSB	
Differential Nonlinearity error	-	-	- 1.9	-	+ 1.9	LSB	
Zero transition voltage	V _{OT}	ANn	Тур - 20	AV _{SS} + 0.5LSB	Typ + 20	mV	
Full scale transition voltage	V _{FST}	ANn	Тур - 20	AVRH- 1.5LSB	Typ + 20	mV	
Commons 4: *			1.0	-	5.0	μs	4.5V ≤ AV _{CC} ≤ 5.5V
Compare time*	-	-	2.2	-	8.0	μs	2.7V ≤ AV _{CC} <4.5V
Commilia a time a*			0.5	-	-	μs	4.5V ≤ AV _{CC} ≤ 5.5V
Sampling time*	-	-	1.2	-	-	μs	2.7V ≤ AV _{CC} <4.5V
Power supply current	I _A		-	2.0	3.1	mA	A/D Converter active
	I _{AH}	AV _{CC}	-	-	3.3	μΑ	A/D Converter not operated
Reference power supply current	I _R	AVRH	-	520	810	μΑ	A/D Converter active
(between AVRH and $AV_{SS})$	I _{RH}	AVKII	-	-	1.0	μΑ	A/D Converter not operated
Analog input capacity	C _{VIN}	ANn	-	-	15.6	pF	
Analog impodence	В	ANn	=	-	2050	Ω	4.5V ≤ AV _{CC} ≤ 5.5V
Analog impedance	R _{VIN}	AINII	-	-	3600	Ω	2.7V ≤ AV _{CC} < 4.5V
Analog port input current (during conversion)	I _{AIN}	ANn	- 0.3	-	+ 0.3	Ω	AV _{SS} <v<sub>AIN <av<sub>CC, AVRH</av<sub></v<sub>
Analog input voltage	V _{AIN}	ANn	AV _{SS}	-	AVRH	V	
Reference voltage range	-	AVRH	AV _{CC} - 0.1	-	AV _{CC}	V	
Variation between channels	-	ANn	-	-	4.0	LSB	

^{*:} Time for each channel.

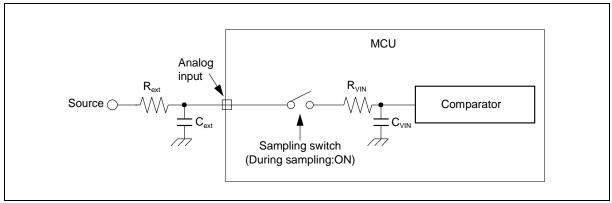
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14.5.2 Accuracy and Setting of the A/D Converter Sampling Time

If the external impedance is too high or the sampling time too short, the analog voltage charged to the internal sample and hold capacitor is insufficient, adversely affecting the A/D conversion precision.

To satisfy the A/D conversion precision, a sufficient sampling time must be selected. The required sampling time (Tsamp) depends on the external driving impedance R_{ext} , the board capacitance of the A/D converter input pin C_{ext} and the AV_{CC} voltage level. The following replacement model can be used for the calculation:



Rext: External driving impedance

Cext: Capacitance of PCB at A/D converter input

C_{VIN}: Analog input capacity (I/O, analog switch and ADC are contained)

RVIN: Analog input impedance (I/O, analog switch and ADC are contained)

The following approximation formula for the replacement model above can be used:

Tsamp = $7.62 \times (Rext \times Cext + (Rext + R_{VIN}) \times C_{VIN})$

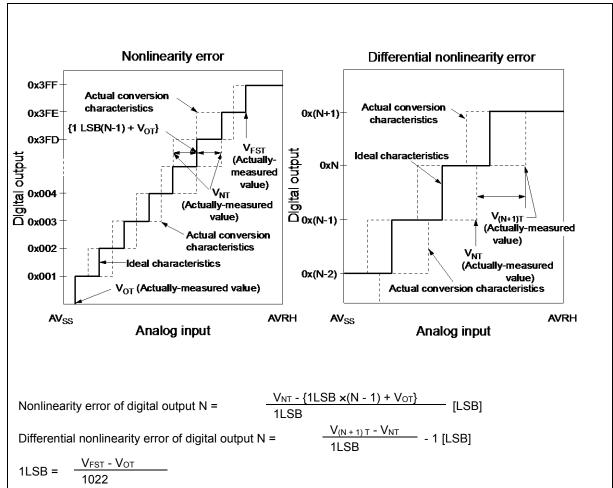
- Do not select a sampling time below the absolute minimum permitted value. (0.5µs for 4.5V ≤ AV_{CC} ≤ 5.5V, 1.2µs for 2.7V ≤ AV_{CC} < 4.5V)</p>
- If the sampling time cannot be sufficient, connect a capacitor of about 0.1μF to the analog input pin.
- A big external driving impedance also adversely affects the A/D conversion precision due to the pin input leakage current IIL (static current before the sampling switch) or the analog input leakage current IAIN (total leakage current of pin input and comparator during sampling). The effect of the pin input leakage current IIL cannot be compensated by an external capacitor.
- The accuracy gets worse as |AVRH AV_{SS}| becomes smaller.

14.5.3 Definition of A/D Converter Terms

- Resolution : Analog variation that is recognized by an A/D converter.
- Nonlinearity error : Deviation of the actual conversion characteristics from a straight line that connects the zero transition point (0b0000000000 ←→ 0b0000000001) to the full-scale transition point (0b11111111110 ←→ 0b1111111111).
- Differential nonlinearity error: Deviation from the ideal value of the input voltage that is required to change the output code by 1LSB.
- Total error : Difference between the actual value and the theoretical value. The total error includes zero transition error, full-scale transition error and nonlinearity error.
- Zero transition voltage: Input voltage which results in the minimum conversion value.
- Full scale transition voltage: Input voltage which results in the maximum conversion value.

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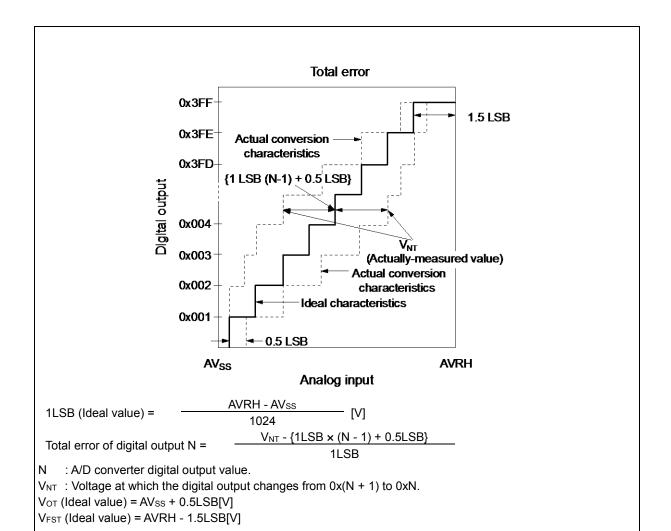


N : A/D converter digital output value.

 V_{O} : Voltage at which the digital output changes from 0x000 to 0x001. V_{FST}: Voltage at which the digital output changes from 0x3FE to 0x3FF. V_{NT}: Voltage at which the digital output changes from 0x(N - 1) to 0xN.

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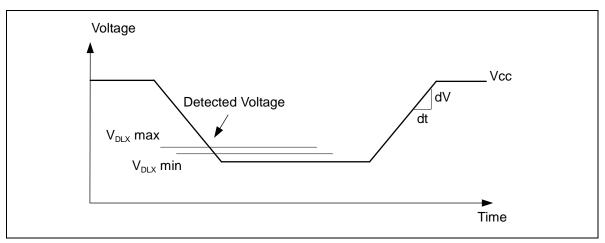
14.6 Low Voltage Detection Function Characteristics

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C)$

				Value			
Parameter	Symbol	Symbol Conditions Min		Тур	Max	Unit	
	V_{DL0}	CILCR:LVL = 0000 _B	2.70	2.90	3.10	V	
	V _{DL1}	CILCR:LVL = 0001 _B	2.79	3.00	3.21	V	
	V _{DL2}	CILCR:LVL = 0010 _B	2.98	3.20	3.42	V	
Detected voltage[1]	V _{DL3}	CILCR:LVL = 0011 _B	3.26	3.50	3.74	V	
	V_{DL4}	CILCR:LVL = 0100 _B	3.45	3.70	3.95	V	
	V _{DL5}	CILCR:LVL = 0111 _B	3.73	4.00	4.27	V	
	V _{DL6}	CILCR:LVL = 1001 _B	3.91	4.20	4.49	V	
Power supply voltage change rate ^[2]	dV/dt	-	- 0.004	-	+ 0.004	V/µs	
	.,	CILCR:LVHYS=0	-	-	50	mV	
Hysteresis width	V _{HYS}	CILCR:LVHYS=1	80	100	120	mV	
Stabilization time	T _{LVDSTAB}	-	-	-	75	μs	
Detection delay time	t _d	-	-	-	30	μs	

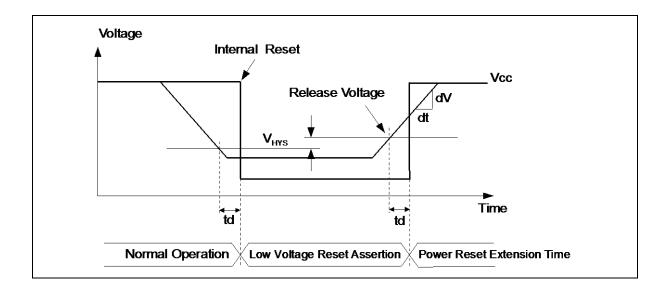
^{[1]:} If the power supply voltage fluctuates within the time less than the detection delay time (t_d) , there is a possibility that the low voltage detection will occur or stop after the power supply voltage passes the detection range.

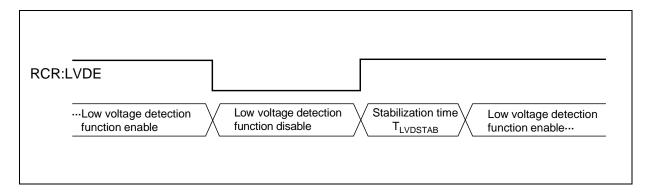
[2]: In order to perform the low voltage detection at the detection voltage (V_{DLX}), be sure to suppress fluctuation of the power supply voltage within the limits of the change ration of power supply voltage.



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14.7 Flash Memory Write/Erase Characteristics

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C)$

Parameter.		Conditions		Value		11-14	Damanta	
Parar	Parameter		Min	Тур	Max	Unit	Remarks	
	Large Sector	Ta≤+105°C	-	1.6	7.5	s		
Sector erase time	Small Sector	-	-	0.4	2.1	s	Includes write time prior to internal erase.	
	Security Sector	-	-	0.31	1.65	s		
Word (16-bit) write	Large Sector	Ta≤+105°C	-	25	400	μs	Not including system-level	
time	Small Sector	-	-	25	400	μs	overheadtime.	
Chip erase time		Ta ≤ + 105°C	-	5.11	25.05	s	Includes write time prior to internal erase.	

Note:

While the Flash memory is written or erased, shutdown of the external power (V_{CC}) is prohibited. In the application system where the external power (V_{CC}) might be shut down while writing or erasing, be sure to turn the power off by using a low voltage detection function.

To put it concrete, change the external power in the range of change ration of power supply voltage $(-0.004V/\mu s)$ to $+0.004V/\mu s$) after the external power falls below the detection voltage $(V_{DLX})^{*1}$.

Write/Erase cycles and data hold time

Write/Erase cycles (cycle)	Data hold time (year)
1,000	20 [2]
10,000	10 [2]
100,000	5 [2]

[1]:See "14.6 Low Voltage Detection Function Characteristics".

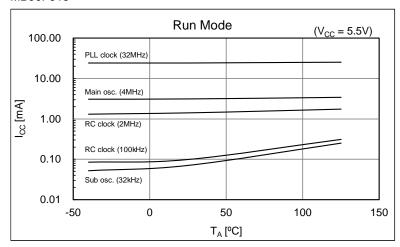
[2]:This value comes from the technology qualification (using Arrhenius equation to translate high temperature measurements into normalized value at + 85°c).

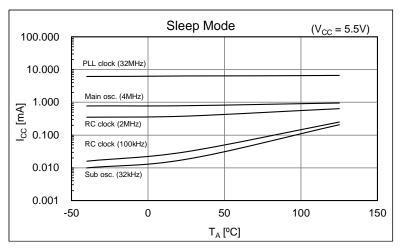
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15. Example Characteristics

This characteristic is an actual value of the arbitrary sample. It is not the guaranteed value. MB96F615

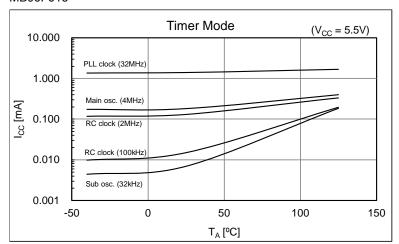


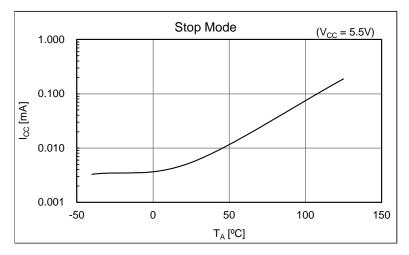


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MB96F615







Used setting

Mode	Selected Source Clock	Clock/Regulator and FLASH Settings
Run mode	PLL	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 32MHz
	Main osc.	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 4MHz
	RC clock fast	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 2MHz
	RC clock slow	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 100kHz
	Sub osc.	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 32kHz
Sleep mode	PLL	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 32MHz
		Regulator in High Power Mode, (CLKB is stopped in this mode)
	Main osc.	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 4MHz
		Regulator in High Power Mode, (CLKB is stopped in this mode)
	RC clock fast	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 2MHz
		Regulator in High Power Mode, (CLKB is stopped in this mode)
	RC clock slow	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 100kHz
		Regulator in Low Power Mode, (CLKB is stopped in this mode)
	Sub osc.	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 32kHz
		Regulator in Low Power Mode, (CLKB is stopped in this mode)
Timer mode	PLL	CLKMC = 4MHz, CLKPLL = 32MHz
		(System clocks are stopped in this mode) Regulator in High Power Mode, FLASH in Power-down / reset mode
	Main osc.	CLKMC = 4MHz
		(System clocks are stopped in this mode) Regulator in High Power Mode, FLASH in Power-down / reset mode
	RC clock fast	CLKMC = 2MHz
		(System clocks are stopped in this mode) Regulator in High Power Mode, FLASH in Power-down / reset mode
	RC clock slow	CLKMC = 100kHz
		(System clocks are stopped in this mode) Regulator in Low Power Mode, FLASH in Power-down / reset mode
	Sub osc.	CLKMC = 32 kHz
		(System clocks are stopped in this mode)
		Regulator in Low Power Mode, FLASH in Power-down / reset mode
Stop mode	stopped	(All clocks are stopped in this mode)
		Regulator in Low Power Mode, FLASH in Power-down / reset mode

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16. Ordering Information

MCU with CAN controller

Part number	Flash memory	Package*		
MB96F612RBPMC-GSE1				
MB96F612RBPMC-GS-UJE1				
MB96F612RBPMC-GSE2	Flash A (64.5KB)	48-pin plastic LQFP (LQA048)		
MB96F612RBPMC-GS-UJE2				
MB96F612RBPMC-GTE1				
MB96F613RBPMC-GSE1				
MB96F613RBPMC-GS-UJE1				
MB96F613RBPMC-GSE2	Flash A (96.5KB)	48-pin plastic LQFP (LQA048)		
MB96F613RBPMC-GS-UJE2				
MB96F613RBPMC-GTE1				
MB96F615RBPMC-GSE1				
MB96F615RBPMC-GS-UJE1				
MB96F615RBPMC-GSE2	Flash A (160.5KB)	48-pin plastic LQFP (LQA048)		
MB96F615RBPMC-GS-UJE2				
MB96F615RBPMC-GTE1				

^{*:} For details about package, see "Package Dimension".

MCU without CAN controller

Part number	Flash memory	Package*		
MB96F612ABPMC-GSE1				
MB96F612ABPMC-GS-UJE1				
MB96F612ABPMC-GSE2	Flash A (64.5KB)	48-pin plastic LQFP (LQA048)		
MB96F612ABPMC-GS-UJE2	()			
MB96F612ABPMC-GTE1				
MB96F613ABPMC-GSE1		48-pin plastic LQFP (LQA048)		
MB96F613ABPMC-GS-UJE1				
MB96F613ABPMC-GSE2	Flash A (96.5KB)			
MB96F613ABPMC-GS-UJE2	(**************************************			
MB96F613ABPMC-GTE1				
MB96F615ABPMC-GSE1				
MB96F615ABPMC-GS-UJE1	Flash A	49 pin plactic LOED (LOAGAS)		
MB96F615ABPMC-GSE2	(160.5KB)	48-pin plastic LQFP (LQA048)		
MB96F615ABPMC-GTE1				

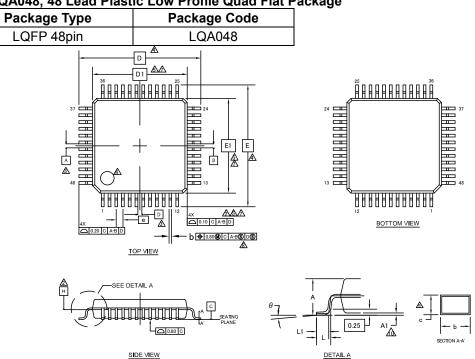
^{*:} For details about package, see "Package Dimension".

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17. Package Dimension

LQA048, 48 Lead Plastic Low Profile Quad Flat Package



SYMBOL	DIM	I EN SIOI	NS.	
STWIBOL	MIN.	NOM.	MAX.	
Α	_		1.70	
A1	0.00	_	0.20	
b	0.15		0.27	
С	0.09		0.20	
D	9.00 BSC			
D1	7	.00 BSC		
е	0.50 BSC			
E	9.00 BSC			
E1	7	.00 BSC		
L	0.45	0.60	0.75	
L1	0.30	0.50	0.70	
θ	0°		8°	

NOTES

- 1. ALL DIMENSIONS ARE IN MILLIMETERS.
- LINE COINCIDENT WITH WHERE THE LEAD EXITS THE BODY.
- $\underline{\&}$ DATUMS A-B AND D TO BE DETERMINED AT DATUM PLANE H.
- ATO BE DETERMINED AT SEATING PLANE C.
- ⚠ DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS 0.25mm PRE SIDE. DIMENSIONS D1 AND E1 INCLUDE MOLD MISMATCH AND ARE DETERMINED
 - AT DATUM PLANE H.
- ⚠ DETAILS OF PIN 1 IDENTIFIER ARE OPTIONAL BUT MUST BE LOCATED WITHIN THE ZONE INDICATED.
- REGARDLESS OF THE RELATIVE SIZE OF THE UPPER AND LOWER BODY SECTIONS. DIMENSIONS D1 AND E1 ARE DETERMINED AT THE LARGEST FEATURE OF THE BODY EXCLUSIVE OF MOLD FLASH AND GATE BURRS. BUT INCLUDING ANY MISMATCH BETWEEN THE UPPER AND LOWER SECTIONS OF THE MOLDER BODY.
- ADIMENSION & DOES NOT INCLUDE DAMBER PROTRUSION. THE DAMBAR PROTRUSION (S) SHALL NOT CAUSE THE LEAD WIDTH TO EXCEED b MAXIMUM BY MORE THAN 0.08mm, DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OR THE LEAD FOOT.
- $\underline{\mathbb{A}}$ THESE DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN 0.10mm AND 0.25mm FROM THE LEAD TIP.
- 10 A1 IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT OF THE PACKAGE BODY.

002-13731 **

PACKAGE OUTLINE, 48 LEAD LQFP 7.0X7.0X1.7 MM LQA048 REV**

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18. Major Changes

Spansion Publication Number: MB96610_DS704-00007

Page	Section	Change Results
Revision 3	.0	
	■FEATURES	Changed the description of "External Interrupts"
4		Interrupt mask and pending bit per channel
		Interrupt mask bit per channel
23 to 26	■HANDLING PRECAUTIONS	Added a section
	■ELECTRICAL CHARACTERISTICS	Changed the Conditions for I _{CCSRCH}
	3. DC Characteristics	CLKS1/2 = CLKB = CLKP1/2 = CLKRC = 2MHz,
0.4	(1) Current Rating	CLKS1/2 = CLKP1/2 = CLKRC = 2MHz,
34		Changed the Conditions for I _{CCSRCL}
		CLKS1/2 = CLKB = CLKP1/2 = CLKRC = 100kHz
		CLKS1/2 = CLKP1/2 = CLKRC = 100kHz
	7	Changed the Conditions for I _{CCTPLL}
		PLL Timer mode with CLKP1 = 32MHz
		PLL Timer mode with CLKPLL = 32MHz
		Changed the Value of "Power supply current in Timer modes"
		I _{CCTPLL}
		Typ: $2480\mu A \rightarrow 1800\mu A \ (T_A = +25^{\circ}C)$
0.5		Max: $2710\mu A \rightarrow 2245\mu A \ (T_A = +25^{\circ}C)$
35		Max: $3985\mu A \rightarrow 3165\mu A \ (T_A = +105^{\circ}C)$
		Max: $4830\mu A \rightarrow 3975\mu A (T_A = +125^{\circ}C)$
		Changed the Conditions for I _{CCTRCL}
		RC Timer mode with CLKRC = 100kHz,
		SMCR:LPMSS = 0 (CLKPLL, CLKMC and CLKSC stopped)
		RC Timer mode with CLKRC = 100kHz
		(CLKPLL, CLKMC and CLKSC stopped)
		Changed the annotation *2
		Power supply for "On Chip Debugger" part is not included.
36		Power supply current in Run mode does not include
		Flash Write / Erase current.
		The current for "On Chip Debugger" part is not included.
47	5. A/D Converter (2) Accuracy and Setting of the A/D Converter Sampling Time	Deleted the unit "[Min]" from approximation formula of Sampling time
	7. Flash Memory Write/Erase Characteristics	Changed the condition
52		$(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, VD=1.8V\pm0.15V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C)$
		$(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}\text{C to } + 125^{\circ}\text{C})$

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Page	Section	Change Results
	■ELECTRICAL CHARACTERISTICS	Changed the Note
52	7. Flash Memory Write/Erase Characteristics	While the Flash memory is written or erased, shutdown of the external power ($V_{\rm CC}$) is prohibited. In the application system where the external power ($V_{\rm CC}$) might be shut down while writing, be sure to turn the power off by using an external voltage detector.
		While the Flash memory is written or erased, shutdown of the external power ($V_{\rm CC}$) is prohibited. In the application system where the external power ($V_{\rm CC}$) might be shut down while writing or erasing, be sure to turn the power off by using a low voltage detection function.
	■ORDERING INFORMATION	Deleted the Part number
		MCU with CAN controller
		MB96F612RBPMC-GTE2
		MB96F613RBPMC-GTE2
56		MB96F615RBPMC-GTE2
		MCU without CAN controller
		MB96F612ABPMC-GTE2
		MB96F613ABPMC-GTE2
		MB96F615ABPMC-GTE2
Revision 3	3.1	
-	-	Company name and layout design change
Rev.*B		
	1. Product Lineup	
6, 8, 58,	3. Pin Assignment	Package description modified to JEDEC description.
59	16. Ordering Information	FPT-48P-M26 → LQA048
	17. Package Dimension	
		Added the following part number.
		MB96F612RBPMC-GS-UJE1,
		MB96F612RBPMC-GS-UJE2,
		MB96F613RBPMC-GS-UJE1,
		MB96F613RBPMC-GS-UJE2,
		MB96F615RBPMC-GS-UJE1,
58	16. Ordering Information	MB96F615RBPMC-GS-UJE2,
		MB96F612ABPMC-GS-UJE1,
		MB96F612ABPMC-GS-UJE2
		MB96F613ABPMC-GS-UJE1,
		MB96F613ABPMC-GS-UJE2
		MB96F615ABPMC-GS-UJE1,
		MB96F615ABPMC-GS-UJE2
Rev.*C		
58	16. Ordering Information	Deleted the Part number
		MCU without CAN controller
		MB96F615ABPMC-GS-UJE2

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Document History

Document Title: MB96610 Series, F²MC, 16FX, 16-bit Proprietary Microcontroller

Document Number: 002-04709

Revision	ECN	Orig. of Change	Submission Date	Description of Change
**	ı	KSUN	01/31/2014	Migrated to Cypress and assigned document number 002-04709. No change to document contents or format.
*A	5146534	KSUN	02/29/2016	Updated to Cypress template
*B	5735123	KUME	05/15/2017	Updated the Ordering Information and the Package Dimension For details, please see 18. Major Changes.
*C	5809040	MIYH	07/11/2017	Updated the Ordering Information For details, please see 18. Major Changes.

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